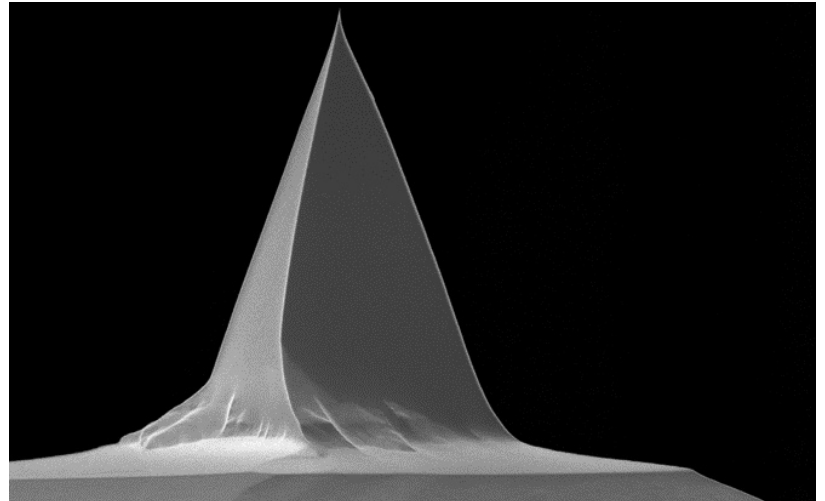


SHOCONA Probes

Model ID: SHOCONA-10

SHOCONA Probes are compatible with most commercially available SPMs. These probes are nanofabricated using highly doped single crystal silicon with unparalleled reproducibility, robustness and sharpness for consistent high resolution imaging capabilities.

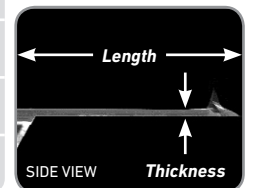
SHOCONA Probes are designed for contact mode applications with a shorter length, providing better sensitivity without compromising on spring constant requirements. The reflex side is coated with aluminum for increased laser signal quality.



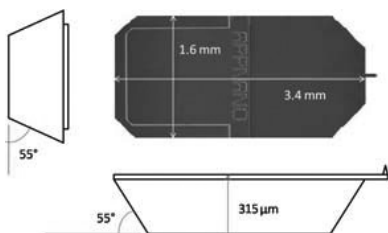
TIP SPECIFICATIONS	
Shape	Pyramidal
Height (μm)	14-16
ROC (nm)	6
Coating	None

CANTILEVER SPECIFICATIONS	
Material	Si
Shape	Rectangular
Coating	Al, 50 nm ± 5 nm

PARAMETER	NOMINAL	MINIMUM	MAXIMUM
Spring Constant (N/m)	0.14	0.01	0.60
Frequency (kHz)	21	8	37
Length (μm)	225	215	235
Width (μm)	46	41	51
Thickness (μm)	1.0	0.5	1.5



HANDLE CHIP SPECIFICATIONS	
L x W x T	3.4 mm x 1.6 mm x 315 μm
Alignment Groove	YES



AFMWorkshop offers the SHOCONA Probes in a box of 10. If you would like to order a larger volume, please contact us for more information.

NOTES:

1. The specification range is guaranteed. The values of spring constant and frequency are calculated using mathematical formulation
2. These probes feature alignment grooves compatible with all alignment chips available in the market.